TOSHIBA CMOS DIGITAL INTEGRATED CIRCUIT SILICON MONOLITHIC

# TC74HC00AP, TC74HC00AF, TC74HC00AFN

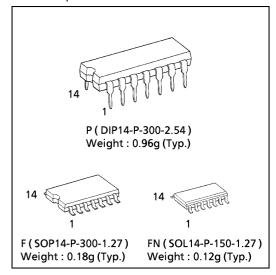
## **QUAD 2-INPUT NAND GATE**

The TC74HC00A is a high speed CMOS 2-INPUT NAND GATE fabricated with silicon gate C2MOS technology. It achieves the high speed operation similar to equivalent LSTTL while maintaining the CMOS low power dissipation. The internal circuit is composed of 3 stages including buffer output, which provide high noise immunity and stable output. All inputs are equipped with protection circuits against static discharge or transient excess voltage.

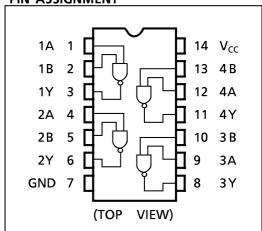
#### FEATURES:

- High Speed······t<sub>pd</sub> = 6ns(typ.) at  $V_{CC} = 5$ V
- High Noise Immunity..... $V_{NIH} = V_{NIL} = 28\% V_{CC}$  (Min.)
- Output Drive Capability ..... 10 LSTTL Loads
- Symmetrical Output Impedance··· | I<sub>OH</sub> | = I<sub>OL</sub> = 4mA(Min.)
- Balanced Propagation Delays ····· t<sub>pLH</sub> ≃ t<sub>pHL</sub>
- Wide Operating Voltage Range ···· V<sub>CC</sub> (opr.) = 2V~6V
- Pin and Function Compatible with 74LS00

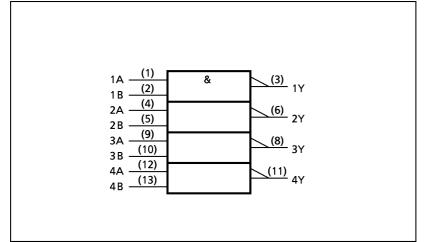
(Note) The JEDEC SOP (FN) is not available in Japan.



#### **PIN ASSIGNMENT**

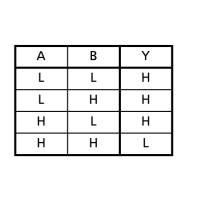


## **IEC LOGIC SYMBOL**



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## TRUTH TABLE



# **ABSOLUTE MAXIMUM RATINGS**

PARAMETER	SYMBOL	VALUE	UNIT
Supply Voltage Range	V <sub>cc</sub>	<b>−</b> 0.5~7	V
DC Input Voltage	V <sub>IN</sub>	$-0.5 \sim V_{CC} + 0.5$	٧
DC Output Voltage	V <sub>OUT</sub>	−0.5~V <sub>CC</sub> + 0.5	٧
Input Diode Current	I <sub>IK</sub>	± 20	mA
Output Diode Current	I <sub>OK</sub>	± 20	mA
DC Output Current	I <sub>OUT</sub>	± 25	mA
DC V <sub>CC</sub> / Ground Current	I <sub>cc</sub>	± 50	mA
Power Dissipation	P <sub>D</sub>	500 (DIP)* / 180 (SOP)	mW
Storage Temperature	T <sub>stg</sub>	<b>−65~150</b>	°C

\*500mW in the range of Ta=  $-40^{\circ}\text{C}\sim65^{\circ}\text{C}$ . From Ta=65°C to 85°C a derating factor of  $-10\text{mW}/^{\circ}\text{C}$  shall be applied until 300mW.

## **RECOMMENDED OPERATING CONDITIONS**

PARAMETER	SYMBOL	VALUE	UNIT
Supply Voltage	V <sub>cc</sub>	2~6	V
Input Voltage	V <sub>IN</sub>	0~V <sub>cc</sub>	V
Output Voltage	V <sub>OUT</sub>	0~V <sub>cc</sub>	V
Operating Temperature	T <sub>opr</sub>	<b>−40~85</b>	°C
Input Rise and Fall Time	t <sub>r</sub> , t <sub>f</sub>	$0 \sim 1000 (V_{CC} = 2.0V)$ $0 \sim 500 (V_{CC} = 4.5V)$ $0 \sim 400 (V_{CC} = 6.0V)$	ns

## DC ELECTRICAL CHARACTERISTICS

DADAMETED	CVARDO	TEST CO	MDITION	$V_{CC}$ Ta = 25		Ta = 25°0	С	$Ta = -40 \sim 85^{\circ}C$		UNIT
PARAMETER SYMBOL		TEST CONDITION		(V)	MIN.	TYP.	MAX.	MIN.	MAX.	
High - Level Input Voltage	VIH			2.0 4.5 6.0	1.50 3.15 4.20	_ _ _	_ _ _	1.50 3.15 4.20	_	V
Low - Level Input Voltage	VIL			2.0 4.5 6.0	_ _ _	_ _ _	0.50 1.35 1.80		0.50 1.35 1.80	V
High - Level Output Voltage	V <sub>OH</sub>	V <sub>OH</sub> V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>	$I_{OH} = -20\mu A$	2.0 4.5 6.0	1.9 4.4 5.9	2.0 4.5 6.0	_ _ _	1.9 4.4 5.9	_ _ _	V
			$I_{OH} = -4 \text{ mA}$ $I_{OH} = -5.2 \text{ mA}$	4.5 6.0	4.18 5.68	4.31 5.80	_	4.13 5.63	_	
Low - Level Output Voltage	V <sub>OL</sub>	V <sub>I N</sub> =	I <sub>OL</sub> = 20μΑ	2.0 4.5 6.0	_ _ _	0.0 0.0 0.0	0.1 0.1 0.1		0.1 0.1 0.1	v
	V <sub>IH</sub> or V <sub>IL</sub>	$I_{OL} = 4  mA$ $I_{OL} = 5.2  mA$	4.5 6.0	_	0.17 0.18	0.26 0.26	_	0.33 0.33		
Input Leakage Current	I <sub>IN</sub>	$V_{IN} = V_{CC}$ or GND		6.0	_	1	± 0.1	_	± 1.0	
Quiescent Supply Current	I <sub>cc</sub>	$V_{IN} = V_{CC}$ or GND		6.0	_	_	1.0	_	10.0	$\mu$ A

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AC ELECTRICAL CHARACTERISTICS ( $C_L = 15pF$ ,  $V_{CC} = 5V$ ,  $Ta = 25^{\circ}C$ , Input  $t_r = t_f = 6ns$ )

PARAMETER	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Output Transition Time	t <sub>TLH</sub> t <sub>THL</sub>		_	4	8	ns
Propagation Delay Time	t <sub>pLH</sub> t <sub>pHL</sub>		_	6	12	

# AC ELECTRICAL CHARACTERISTICS ( $C_L = 50pF$ , Input $t_r = t_f = 6ns$ )

PARAMETER	SYMBOL	TEST CONDITION		Ta = 25°C		Ta = −40~85°C		UNIT	
FARAIVIETER			V <sub>CC</sub> (V)	MIN.	TYP.	MAX.	MIN.	MAX.	UNIT
	t <sub>TLH</sub>		2.0	-	25	75	_	95	
Output Transition Time			4.5	_	7	15	l —	19	
	t <sub>THL</sub>		6.0	_	6	13	_	16	ns
	t <sub>pLH</sub>		2.0	-	27	75	_	95	
Propagation Delay Time			4.5	_	9	15	-	19	
	t <sub>pHL</sub>		6.0	_	8	13	_	16	
Input Capacitance	C <sub>IN</sub>				5	10	_	10	2
Power Dissipation Capacitance	C <sub>PD</sub> (1)				20	_	_	_	pF

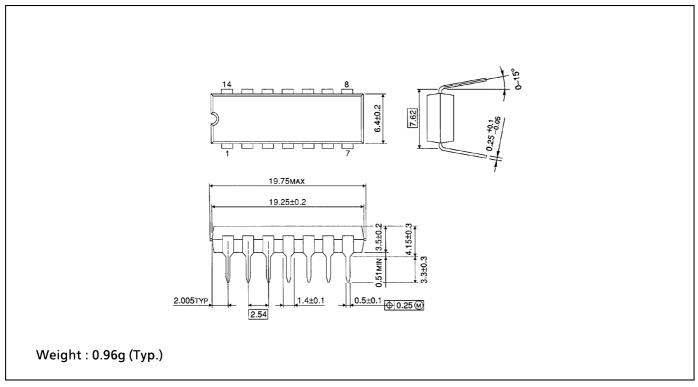
Note (1) C<sub>PD</sub> is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

Average operating current can be obtained by the equation:

 $I_{CC}$  (opr) =  $C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC} / 4$  (per Gate)

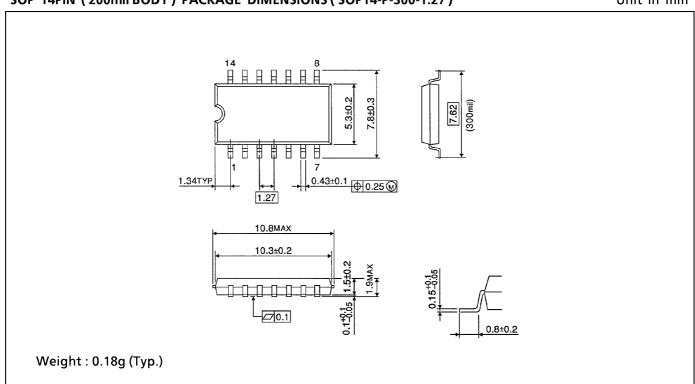
# DIP 14PIN PACKAGE DIMENSIONS (DIP14-P-300-2.54)

Unit in mm



# SOP 14PIN (200mil BODY) PACKAGE DIMENSIONS (SOP14-P-300-1.27)

Unit in mm

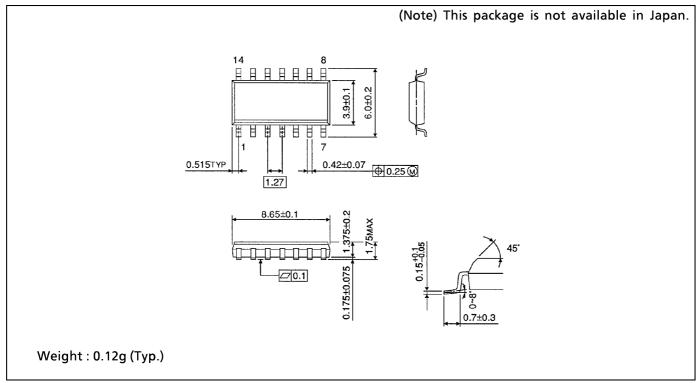


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# SOP 14PIN (150mil BODY) PACKAGE DIMENSIONS (SOL14-P-150 -1.27)

Unit in mm



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